

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**Applicants:** A. Bhavnagarwala et al.

**Examiner:** West, Jeffrey R.

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**Group:** Art Unit 2857

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**For:** **CIRCUITS AND METHODS FOR CHARACTERIZING RANDOM VARIATIONS IN DEVICE CHARACTERISTICS IN SEMICONDUCTOR INTEGRATED CIRCUITS**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313

**AMENDMENT UNDER 37 CFR 1.116**

This paper is in response to the Decision on Appeal dated March 23, 2011.